

<b>Notice of References Cited</b>	Application/Control No. 09/613,190		Applicant(s)/Patent Under Reexamination HUSSAIN ET AL.	
	Examiner Anil Khatri		Art Unit 2124	Page 1 of 1

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X	C	US-6,678,883	01-2004	Berry et al.	717/128
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	M	US-			

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.